

<b>Notice of References Cited</b>	Application/Control No. 10/649,516	Applicant(s)/Patent Under Reexamination STEIJER ET AL.	
	Examiner Derek L. Dupuis	Art Unit 2883	Page 1 of 1

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*	B	US-6,309,113 B1	10-2001	Naito, Katsuyoshi	385/88
*	C	US-5,675,685	10-1997	Fukuda et al.	385/89
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	M	US-			

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**NON-PATENT DOCUMENTS**

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